

January 1990  
Edition 1.1T-33-13  
**FUJITSU**

PRODUCT PROFILE

**2SC3846****Silicon High Speed Power Transistor**

2SC3846 800V, 6A

## ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Conditions	Rating	Unit
Storage Temperature Range	$T_{stg}$		-55 ~ +150	°C
Junction Temperature	$T_J$		+150	°C
Collector to Base Voltage	$V_{CBO}$		1200	V
Emitter to Base Voltage	$V_{EBO}$		7	V
Collector to Emitter Voltage	$V_{CEO}$		800	V
Collector Current	$I_C$		6	A
	$I_{CM}$	$P_W \leq 25\mu s, D.R. \leq 50\%$	10	
Base Current	$I_B$		3	A
Collector Power Dissipation	$P_C$	$T_C = 25^\circ C$	80	W

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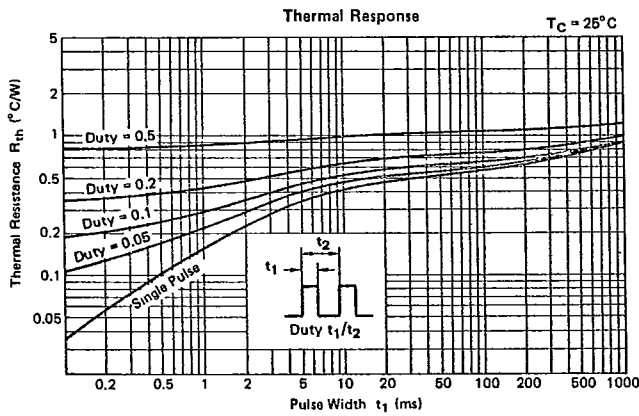
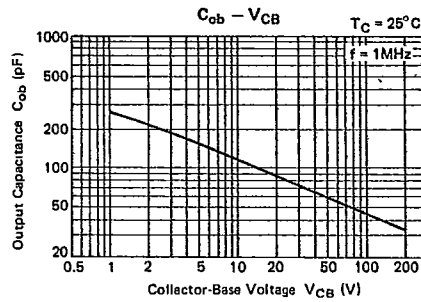
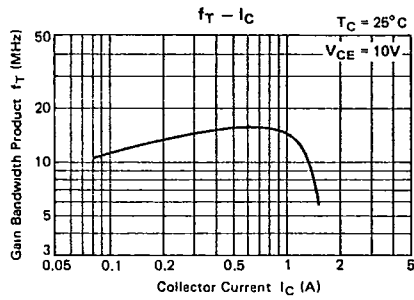
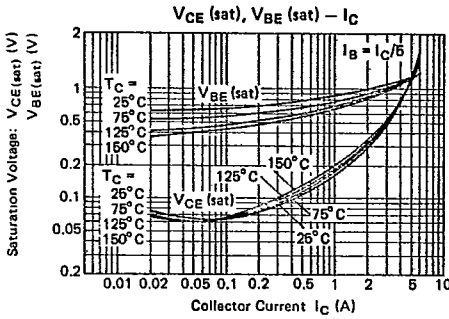
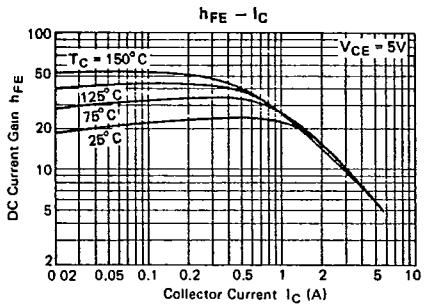
ELECTRICAL CHARACTERISTICS ( $T_a = 25^\circ C$ )

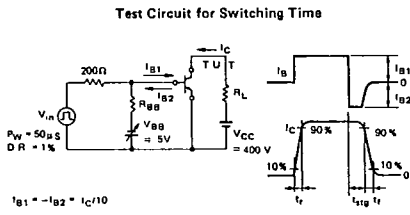
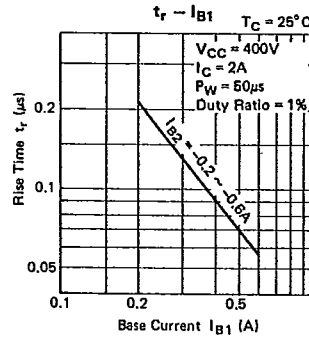
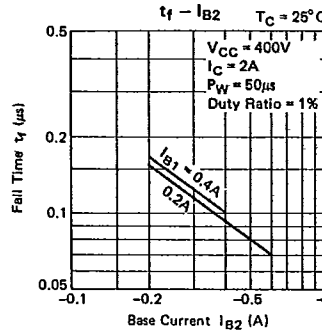
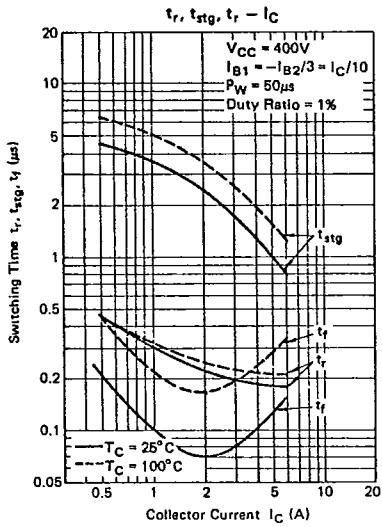
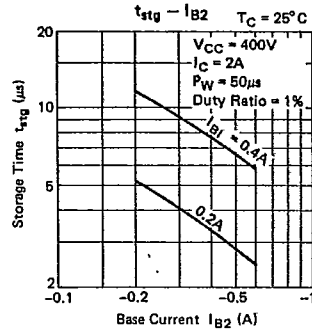
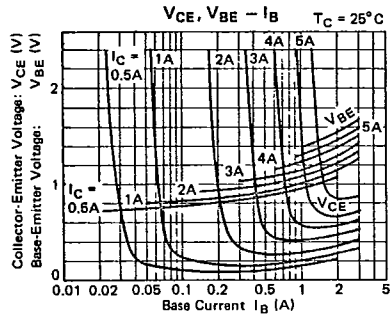
Parameter	Symbol	Test Conditions	Limit			Unit
			Min.	Typ.	Max.	
Collector to Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C = 1mA, I_E = 0$	1200	—	—	V
Emitter to Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E = 1mA, I_C = 0$	7	—	—	V
Collector to Emitter Sustaining Voltage	$V_{(BR)CEO}$	$I_C = 10mA, R_{BE} = \infty \Omega$	800	—	—	V
Collector to Emitter Sustaining Voltage	$V_{CEX(SUS)}$	$I_C = 5A, I_{B2} = -0.6A, L = 1mA^*$	900	—	—	V
Collector Cutoff Current	$I_{CBO}$	$V_{CB} = 1000V, I_E = 0$	—	—	100	$\mu A$
		$V_{CB} = 1000V, I_E = 0, T_a = 100^\circ C$	—	—	1	mA
Emitter Cutoff Current	$I_{EBO}$	$V_{EB} = 6V, I_C = 0$	—	—	100	$\mu A$
DC Current Gain	$h_{FE}$	$V_{CE} = 5V, I_C = 2A^{**}$	10	15	30	—
Collector to Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = 2A, I_B = 0.4A^{**}$	—	0.3	1.5	V
Base to Emitter Saturation Voltage	$V_{BE(sat)}$		—	1.0	2.0	V
Output Capacitance	$C_{ob}$	$V_{CB} = 10V, I_E = 0, f = 1MHz$	—	120	—	pF
Gain Bandwidth Product	$f_T$	$V_{CE} = 10V, I_C = 0.5A$	—	15	—	MHz
Rise Time	$t_r$	$V_{CC} = 400V, I_C = 2A, 3I_{B1} = -I_{B2} = 0.6A^*$	—	0.20	0.5	$\mu s$
Storage Time	$t_{stg}$		—	2.50	3.5	$\mu s$
Fall Time	$t_f$		—	0.07	0.3	$\mu s$

\*1 Test Circuit \*\*2 Pulse  $P_W \leq 300\mu s$ , Duty Ratio  $\leq 6\%$ 

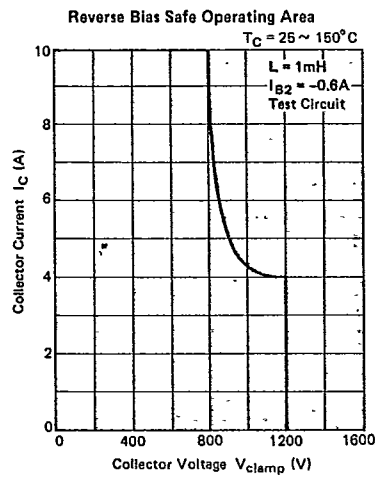
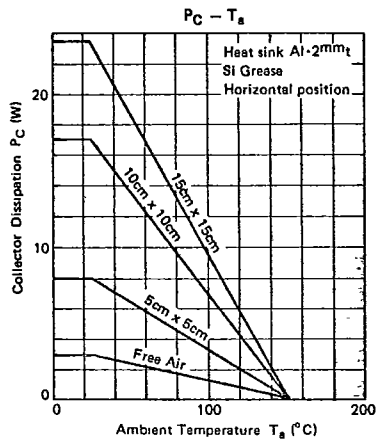
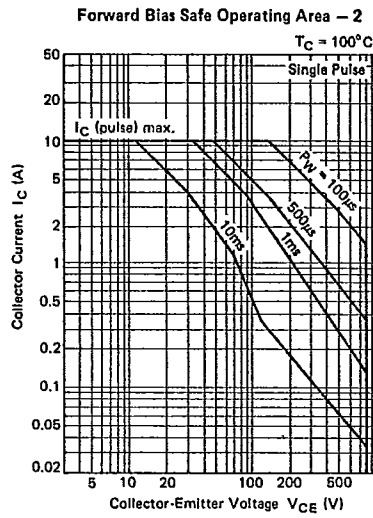
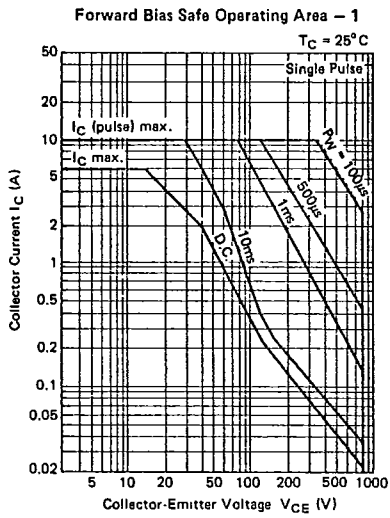
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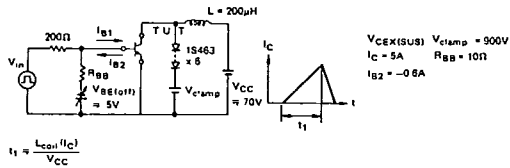




2SC3846



Test Circuit for  $V_{CEX(sus)}$  and Reverse Bias Safe Operating Area



TO-3PF FULL PLASTIC MOLD POWER TRANSISTORS  
(RING EMITTER TRANSISTORS)

ELECTRICAL CHARACTERISTICS

Type No.	Maximum Ratings (T <sub>a</sub> = 25°C)					Electrical Characteristics (T <sub>a</sub> = 25°C)			
	V <sub>CB0</sub> (V)	V <sub>CE0</sub> (V)	I <sub>C</sub> (A)	I <sub>CM</sub> * (A)	P <sub>C</sub> (W)	V <sub>CE</sub> (V)	I <sub>C</sub> (A)	h <sub>FE</sub> Min.	t <sub>f</sub> (μs)
									Max.
2SC3842	600	400	10	15	70	5	5	10	0.3
2SC3843	600	450	10	20	75	5	6	10	0.2
2SC3844	600	450	15	20	75	5	10	10	0.3
2SC3845	1200	800	3	6	75	5	1	10	0.3
2SC3846	1200	800	6	10	80	5	2	10	0.3
2SC3847	1200	800	10	20	85	5	4	10	0.3
2SC3947	850	500	5	8	70	5	2.5	10	0.3
2SC3948	850	500	10	15	75	5	5	10	0.3
2SC3949	850	500	15	20	80	5	10	10	0.3

\* Pulsed P<sub>w</sub> ≤ 25μs, D.R. ≤ 50%

• Package Outline and Terminal Configuration

